



제25회 한국반도체학술대회

The 25th Korean Conference on Semiconductors

2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

2018년 2월 7일(수), 13:15-14:45

Room G (봉래III+III, 6층)

G. Device & Process Modeling, Simulation and Reliability 분과

[WG3-G] Modeling and Simulation II - Device and Process

좌장: 최성진 교수(국민대학교), 홍성민 교수(GIST)

<p>WG3-G-1 13:15-13:30</p>	<p>Physics-Based Capacitance Model of Drift Region in LDMOS and Its Implementation with BSIM4 Jun Hyeok Kim¹, Chan Ho Park¹, Sung Moo Kim¹, Ji-Woon Yang², and Geun Tae Kwon¹ <i>¹Technology Enabling Team, DB Hitek Co., Ltd., Department of Electronics & Information Engineering, Korea University</i></p>
<p>WG3-G-2 13:30-13:45</p>	<p>A Frequency Domain Solver for Maxwell's Equations and Drift-Diffusion Model Jaehyeong Jang and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, Gwangju Institute of Science and Technology</i></p>
<p>WG3-G-3 13:45-14:00</p>	<p>공정 산포 마진 예측을 위한 Process Emulation Tool과 통계적 분석법을 활용한 Process Integration 모델링 Mi-Na Kim, Hyoung-Gyu Choi, Eun-Young Cheon, Seong-Dong Kim, Seokkiu Lee, and Sungjoo Hong <i>Device modeling & Reliability Group, R&D Division, SK Hynix Inc</i></p>
<p>WG3-G-4 14:00-14:15</p>	<p>First Principles Approach to Analyze Defect-induced Multiphonon Transition at the Si-SiO₂ Interface Junsung Park and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, GIST</i></p>
<p>WG3-G-5 14:15-14:30</p>	<p>Characteristics for Self Heating Effects on Stacked Nanosheet FET Hyunsuk Kim, Dokyun Son, Ilho Myeong, Myounggon Kang, and Hyungcheol Shin <i>ISRC and School of Electrical Engineering and Computer Science, Seoul National University</i></p>
<p>WG3-G-6 14:30-14:45</p>	<p>Series Resistance Characterization of Junctionless Transistors D.-Y. Jeon¹, S. J. Park², M. Mouis³, S. Barraud⁴, G.-T. Kim², and G. Ghibaudo³ <i>¹Institute of Advanced Composite Materials, Korea Institute of Science and Technology, ²School of Electrical Engineering, Korea University, ³IMEP-LAHC, Grenoble INP, Minatec, ⁴CEA-LETI Minatec</i></p>